

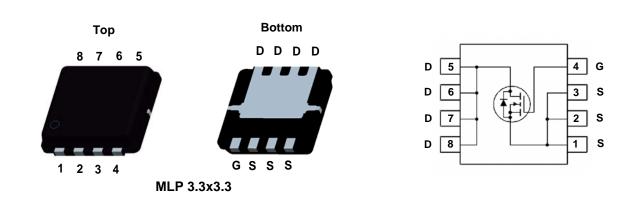
- Typ $Q_q = 12.7$ nC at $V_{GS} = 10V$
- Low Miller charge
- Low Q_{rr} Body Diode
- Optimized efficiency at high frequencies
- UIS Capability (Single Pulse and Repetitive Pulse)
- RoHS Compliant



UltraFET device combines characteristics that enable benchmark efficiency in power conversion applications. Optimized for $r_{DS(on)}$, low ESR, low total and Miller gate charge, these devices are ideal for high frequency DC to DC converters.

Application

- DC/DC converters and Off-Line UPS
- Distributed Power Architectures



MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

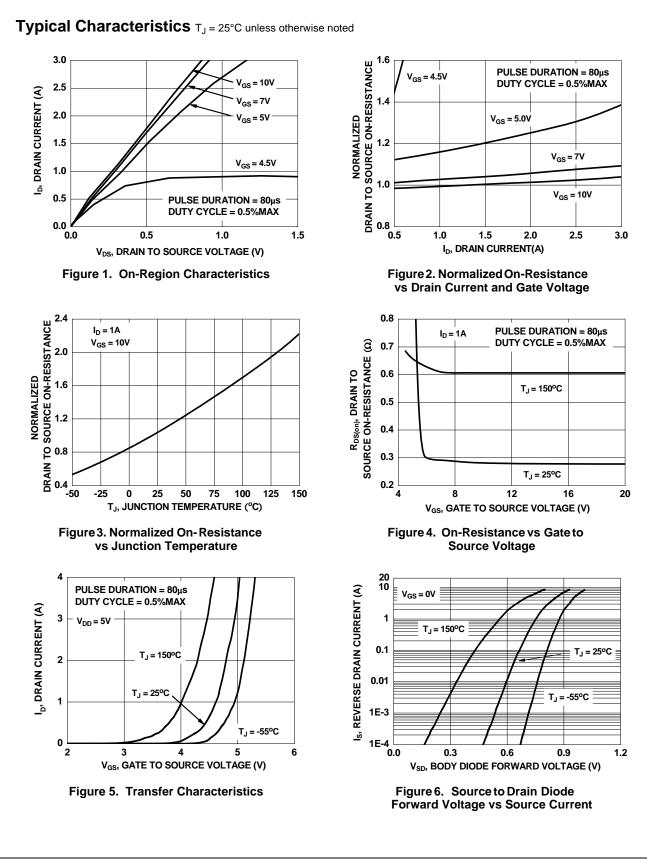
Symbol	Parameter			Ratings	Units	
V _{DS}	Drain to Source Voltage			220	V	
V _{GS}	Gate to Source Voltage			±20	V	
	Drain Current -Continuous (Silicon limited)	T _C = 25°C		7.0		
I _D	-Continuous	T _A = 25°C	(Note 1b)	1.0	Α	
	-Pulsed	13.8		13.8		
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	11	mJ	
P _D	Power Dissipation	T _C = 25°C		42	14/	
	Power Dissipation	T _A = 25°C	(Note 1a)	2.1	W	
T _J , T _{STG}	Operating and Storage Junction Temperature Range			-55 to +150	°C	
Thermal Ch	naracteristics					
R _{0JC}	Thermal Resistance, Junction to Case (Note 1)		(Note 1)	3.0	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note		(Note 1a)	60	-0/00	

R_{0JA} Thermal Resistance, Junction to Ambient Package Marking and Ordering Information

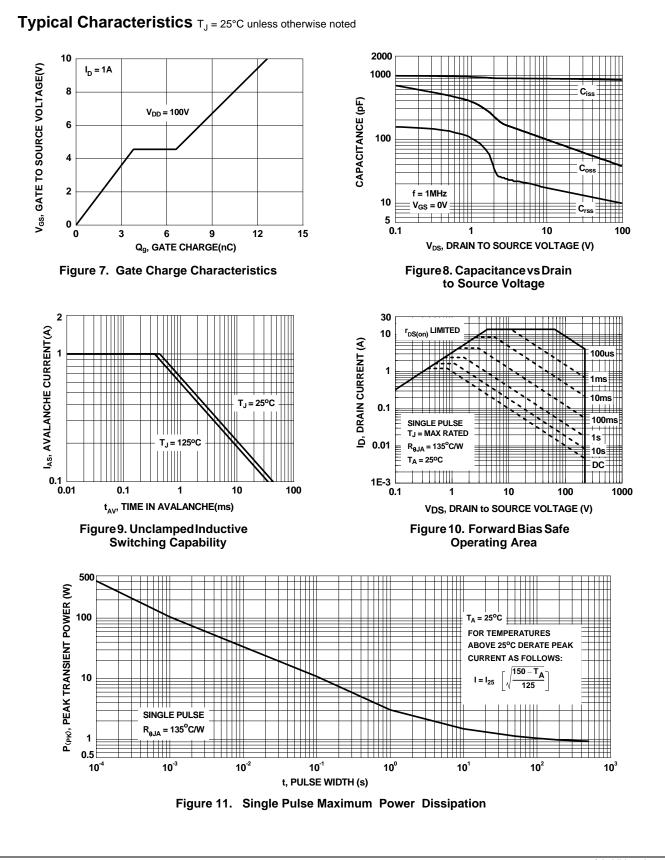
Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC2674	FDMC2674	MLP 3.3X3.3	13 "	12 mm	3000 units

Parameter	Test Conditions	Min	Тур	Max	Units
cteristics					
Drain to Source Breakdown Voltage	$I_{D} = 250 \mu A, V_{GS} = 0 V$	220			V
Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25°C		248		mV/°C
Zero Gate Voltage Drain Current	V _{DS} = 176V, V _{GS} = 0V			1	μΑ
Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100	nA
cteristics			•	-j	
	$V_{CS} = V_{DS}$, $I_D = 250 \mu A$	2	3.4	4	V
Gate to Source Threshold Voltage	$I_D = 250\mu$ A, referenced to 25°C		-10.2		mV/°C
	V _{GS} = 10V, I _D = 1.0A		305	366	
Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 1.0A, T_J = 150^{\circ}C$		678	814	mΩ
Characteristics					
			880	1180	pF
· · ·	V _{DS} = 100V, V _{GS} = 0V, f = 1MHz		70	95	pF
1 1			11	20	pF
Turn-On Delay Time Rise Time Turn-Off Delay Time	$V_{DD} = 100V, I_D = 1.0A$ $V_{GS} = 10V, R_{GEN} = 2.4\Omega$		9 13 15 21	18 23 27	ns ns ns
	$V_{i} = 0 V_{i} t_{0} 10 V_{i} v_{i} = c_{0} v_{i}$				ns nC
-	$V_{GS} = 00.00100 V_{DD} = 150$			10	nC
e e e e e e e e e e e e e e e e e e e					nC
			2.0		no
	$V_{CS} = 0V$, $I_S = 2.2A$ (Note 2)		0.8	1.5	V
				60	ns
,	— I _F = 1.0A, di/dt = 100A/μs			109	nC
	Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Source Leakage Current Cteristics Gate to Source Threshold Voltage Gate to Source Threshold Voltage Temperature Coefficient Static Drain to Source On Resistance Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance Characteristics Turn-On Delay Time Rise Time	Breakdown Voltage Temperature CoefficientID 1×100 Ib $1 = 250 \mu A$, referenced to $25^{\circ}C$ Zero Gate Voltage Drain Current $V_{DS} = 176V$, $V_{GS} = 0V$ Gate to Source Leakage Current $V_{GS} = \pm 20V$, $V_{DS} = 0V$ CteristicsGate to Source Threshold Voltage $I_D = 250 \mu A$, referenced to $25^{\circ}C$ Gate to Source Threshold Voltage $I_D = 250 \mu A$, referenced to $25^{\circ}C$ Static Drain to Source On Resistance $V_{GS} = 10V$, $I_D = 1.0A$ Vasse 10V, $I_D = 1.0A$, $T_J = 150^{\circ}C$ CharacteristicsInput Capacitance $V_{DS} = 100V$, $V_{GS} = 0V$, f = 1MHzCharacteristicsTurn-On Delay Time $V_{DD} = 100V$, $I_D = 1.0A$ Rise Time $V_{DD} = 100V$, $I_D = 1.0A$ Turn-Off Delay Time $V_{GS} = 0V$ to $10V$ Fall Time $V_{DD} = 100V$, $I_D = 1.0A$ Total Gate Charge at $10V$ $V_{GS} = 0V$ to $10V$ Gate to Drain "Miller" Charge $V_{GS} = 0V$, $I_S = 2.2A$ (Note 2)Reverse Recovery Time $I_C = 1.0A$, di/dt = $100A/us$	Breakdown Voltage Temperature Coefficient $I_D = 250\mu$ A, referenced to 25° CZero Gate Voltage Drain Current $V_{DS} = 176$ V, $V_{GS} = 0$ VGate to Source Leakage Current $V_{GS} = \pm 20$ V, $V_{DS} = 0$ VCteristicsGate to Source Threshold Voltage $I_D = 250\mu$ A, referenced to 25° CGate to Source Threshold Voltage $I_D = 250\mu$ A, referenced to 25° CTemperature Coefficient $V_{GS} = 10$ V, $I_D = 1.0A$ Static Drain to Source On Resistance $V_{GS} = 10$ V, $I_D = 1.0A$, $T_J = 150^{\circ}$ CCharacteristicsInput CapacitanceInput Capacitance $V_{DS} = 100$ V, $V_{GS} = 0$ V, f = 1MHzCharacteristicsTurn-On Delay TimeRise Time $V_{DD} = 100$ V, $I_D = 1.0A$ Turn-Off Delay Time $V_{GS} = 10$ V, $I_D = 1.0A$ Fall TimeTotal Gate Charge at 10 VV Gate to Source Gate Charge $I_D = 1.0A$ Gate to Drain "Miller" Charge $V_{GS} = 0$ V, $I_S = 2.2A$ (Note 2)Reverse Recovery Time $I_C = 1.0A$, $d/dt = 100A/\mus$	Breakdown Voltage Temperature CoefficientID 	Breakdown Voltage Temperature CoefficientID ID E 250µA, referenced to 25°C248Zero Gate Voltage Drain Current $V_{DS} = 176V, V_{GS} = 0V$ 1Gate to Source Leakage Current $V_{DS} = 176V, V_{GS} = 0V$ 1CteristicsVGS = ±20V, VDS = 0V±100CteristicsID E 250µA, referenced to 25°C-10.2Gate to Source Threshold VoltageID ID ID ID23.44Gate to Source Threshold VoltageID ID ID ID ID ID10 ID ID ID ID23.44Gate to Source Threshold VoltageID ID ID ID ID ID ID ID ID ID ID ID ID23.44Gate to Source Threshold VoltageID ID

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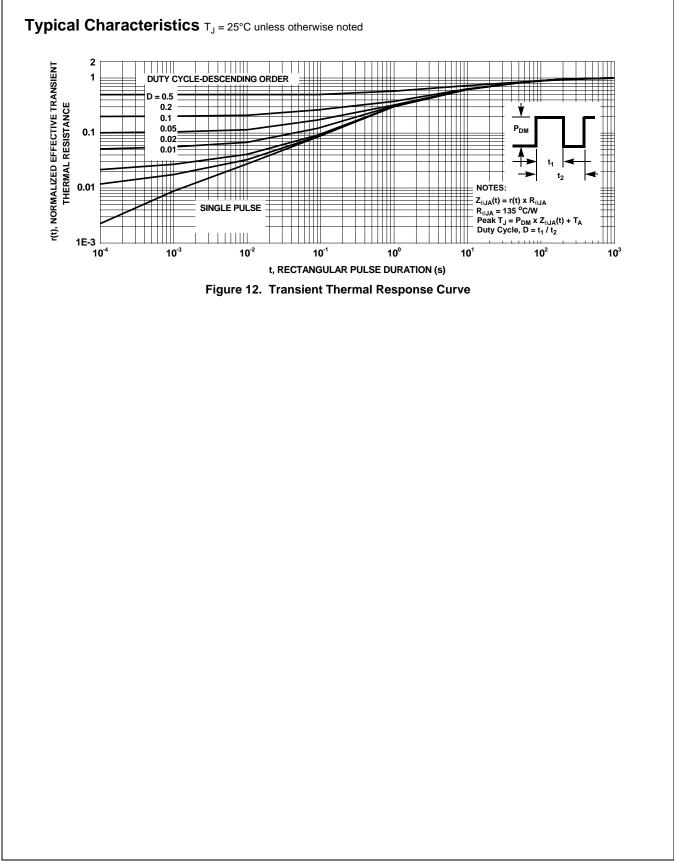
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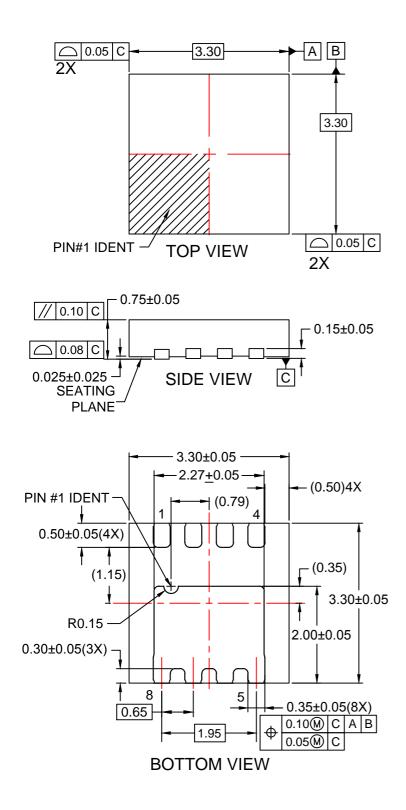
FDMC2674 Rev.F4

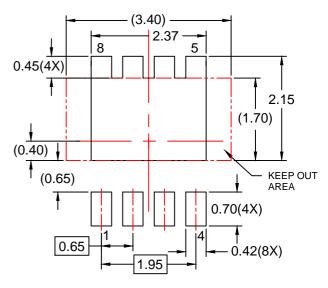
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FDMC2674 N-Channel UltraFET Trench MOSFET



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RECOMMENDED LAND PATTERN

NOTES:

- A. DOES NOT CONFORM TO JEDEC REGISTRATION MO-229
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- D. LAND PATTERN RECOMMENDATION IS EXISTING INDUSTRY LAND PATTERN.
- E. DRAWING FILENAME: MKT-MLP08Srev3.





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